

JPFULL (Japan (JP) Patents Full Text)

Subject Coverage	All patent-relevant areas of science and technology, i.e., all classes of the International Patent Classification		
File Type	Full Text		
Features	Thesauri	International Patent Classification (/IPC), Cooperative Patent Classification (/CPC), European Patent Classification (/EPC and /ICO)	
	Alerts (SDIs)	Weekly or monthly (weekly is the default)	
	CAS Registry Number® Identifiers	<input type="checkbox"/>	Page Images <input type="checkbox"/> STN® AnaVist™ <input type="checkbox"/>
	Keep & Share	<input checked="" type="checkbox"/>	SLART <input checked="" type="checkbox"/> STN Easy® <input type="checkbox"/>
	Learning Database	<input type="checkbox"/>	Structures <input type="checkbox"/>
Record Content	<ul style="list-style-type: none"> • Full text of patent applications, granted patents, and utilities models published in Japan. • Records are available about ten days after publication date with the complete content • Records contain bibliographic data including patent applicant and inventor, patent, application, priority, and related application data, IPC, CPC, EPC, and ICO classification codes, abstract, and full text of description and claims. • Abstracts are either machine translated or taken from equivalent documents if available. Machine translated abstracts of documents with kind code A are replaced by human translated text about three months later. Titles are machine translated, which are in case of kind code A documents replaced by human translations about three month later as well. Descriptions and claims are always machine translated. • Title, patent assignee, and inventor are additionally displayable in Japanese characters • Numeric values of 55 physical and chemical properties are searchable in about 1800 unit variants in all full text fields. • Database records comprise all documents published for one application. • Legal status data, patent and non-patent citations, and family display formats from the INPADOCDB database are available. • Some of the full text has been created by Optical Character Recognition (OCR) software. Therefore, characters may be misinterpreted, or portions of the text may be incomplete. 		
File Size	More than 6.28 million family records with more than 8.8 million publications (02/2019)		
Coverage	Application year 2000 to present		
Updates	Weekly		
Language	English		
Database Producer	Questel 4, rue des Colonnes 75002 Paris France Phone: +8000-783-7835 (Europe), +800-456-7248 (North America, Pacific) Email: help@questel.com Copyright Holder		

Database Supplier FIZ Karlsruhe
STN Europe
P.O. Box 2465
76012 Karlsruhe
Germany
Phone: +49-7247-808-555
Fax: +49-7247-808-259
Email: helpdesk@fiz-karlsruhe.de

Sources Patent applications, granted patents, and utilities models published by the Japan Patent Office

- User Aids**
- Online Helps (HELP DIRECTORY lists all help messages available)
 - STNGUIDE
-

- Clusters**
- AEROTECH
 - ALLBIB
 - AUTHORS
 - CORPSOURCE
 - ENGINEERING
 - FULLTEXT
 - HPATENTS
 - NPS
 - PATENTS
 - PNTTEXT
- [STN Database Clusters](#) information (PDF)
-

Pricing Enter HELP COST at an arrow prompt.

Search and Display Field Codes

If multiple search terms are linked with and AND-operator, all terms are searched in the complete database record, i.e. in all publications referring to one application. For a search in a specific publication of the record, connect the search term and the patent kind code with the (L)-proximity operator, e.g., S BOREHOLE/AB, TI, CLM (L) JPA/PK limits the search to Japanese applications JPA.

Fields that allow left truncation are indicated by an asterisk (*).

General Search Fields

Search Field Name	Search Code	Search Examples	Display Codes
Basic Index* (contains single words from title (TIEN), abstract (AB), detailed description (DETD), claims (CLM), and main claims (MCLM) fields)	None or /BI	S TRANSISTOR AND ELECTRODE S ACOUSTIC SENSOR S ?TRANSFER?	TIEN, AB, DETD, CLM, MCLM
Abstract*	/AB	S BOREHOLE/AB	AB
Accession Number	/AN	S 2011006109/AN	AN
Agent	/AG	S OHARA YOSHIKAZU/AG	AG
Agent Number	/AGN	S 100111442/AGN	AGN
Application Country (WIPO code and text)	/AC	S JP/AC	AI
Application Date (1)	/AD	S AD=JAN 2011	AI
Application Number (2)	/AP (or /APPS)	S JP2011-101353/AP	AI
Application Year (1)	/AY	S AY>=2000	AI
Claims*	/CLM	S DERIVATION/CLM	CLM
Cooperative Patent Classification (3)	/CPC	S C12N0009/CPC	CPC
Cooperative Patent Classification, Action Date	/CPC.ACD	S 20121113/CPC.ACD	CPC.TAB
Cooperative Patent Classification, Keyword	/CPC.KW	S C12N0009/CPC (S) I/CPC.KW	CPC.TAB
Cooperative Patent Classification, Version	/CPC.VER	S 20130101/CPC.VER	CPC.TAB
Document Type (code and text)	/DT (or /TC)	S P/DT S UTILITY MODEL/DT	DT
Entry Date (1)	/ED	S ED=SEP 2012	ED
Entry Date of Fulltext (1)	/EDTX	S 20120926/EDTX	EDTX
European Patent Classification (3)	/EPC (or /ECLA)	S H02K0003-12/EPC	EPC
Field Availability	/FA	S AB/FA	FA
International Patent Classification (ICM, ICS, IPCI, IPCR) (3)	/IPC	S A01B0001-02/IPC	ICM, ICS, IPCI, IPCR
International Patent Classification (ICM, ICS)	/IC	S A45D/IC	IC, ICM, ICS
ICO (in-computer-only) Classification (3)	/ICO	S T04L0025:02C /ICO	ICO
Inventor	/IN (or /AU)	S MASAKI NAGAOKA/IN S MASAKI?/IN	IN
Inventor, Country (WIPO code and text)	/IN.CNY	S JP/IN.CNY	IN, IN.CNY
IPC, Initial	/IPCI	S B21B0001/IPCI	IPCI, IPC
IPC, Keyword Terms	/IPC.KW	S INITIAL/IPC.KW	IPC.TAB
IPC, Main	/ICM	S A63B017-00/ICM	ICM, IC
IPC, Reclassified	/IPCR	S B21D0005-02/IPCR	IPCR, IPC
IPC, Reform	/IPC.REF	S A01B0001-16/IPC.REF	IPC.TAB
IPC, Secondary	/ICS	S A41C003-12/ICS	ICS, IC
IPC, Version	/IPC.VER	S 7/IPC.VER	IPC.TAB
Language (code and text)	/LA	S JA/LA S JAPANESE/LA	LA
Language, Filing (code and text)	/LAF	S JA/LAF S JAPANESE/LAF	LAF
Key Terms (5)	/KT	S GLUCOSE ABSORPTION/KT	KT
Main Claim*	/MCLM	S ?FRACTURE?/MCLM	MCLM
Number of Claims (1)	/CLMN	S 5-7/CLMN	CLMN
Number of Paragraphs in DETD (Detailed Description) (1)	/DETN	S DETN<10	DETN
Patent Applicant/Patentee (4)	/PA (or /CS)	S AISIN SEIKI CO LTD/PA	PA
Patent Applicant, Country	/PA.CNY	S JP/PA.CNY	PA, PA.CNY

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General Search Fields (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Patent Assignee Number Patent Country (WIPO code and text) Patent Information Publication Type	/PAN /PC /PIT	S 300004681/PAN S JP/PC S JPA DOC. LAID OPEN TO PUBL. INSPEC. (PUBLISHED FROM 1971 ONWARDS/PIT	PAN PI PIT
Patent Kind Code Patent Number (2)	/PK /PN (or /PATS)	S JPA/PK S JP 2012070634/PN	PI PI
Patent Number, Original Patent Number/Kind Code Physical Properties Priority Country Priority Country (WIPO code and text) Priority Date (1)	/PNO /PNK /PHP /PRC /PRD	S JP2011062216/PNO S JP2011062572A/PNK S VOLT/PHP (S) TOUCH SCREEN/BI S JP/PRC S JAPAN/PRC S PRD=MAY, 20 2003 S 20030520/PRD	PNO PI KWIC PRN PRN
Priority Date, First (1) Priority Number (2) Priority Number, Original Priority Year (1) Priority Year, First (1) Publication Date (1) Publication Year (1) Related Patent Country Related Application Number Related Application Date (1) Related Application Year (1) Title (English)* Update Date (1)	/PRDF /PRN /PRNO /PRY /PRYF /PD /PY /RLC /RLN /RLD /RLY /TI, /TIEN /UP	S 20010614/PRDF S DE2004-102004063838/PRN S US10054698P/PRNO S 2003/PRY S 2003-2004/PRYF S PD=MARCH-APRIL 2011 S PY>2008 AND L1 S WO/RLC S WO2005-JP19917/RLN S 20050329/RLD S 2005/RLY S FLUID###/TIEN S UP=SEP 2012	PRN PRN PRNO, PRAO PRN PRN PI PI RLI RLI RLI RLI TI, TIEN UP

(1) Numeric search field that may be searched using numeric operators or ranges.

(2) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.

(3) An online thesaurus is available in this field.

(4) Search with implied (S) proximity is available in this field.

(5) Field available for records since 20180813/UP.

Super Search Fields

Enter a super search code to execute a search in one or more fields that may contain the desired information. Super search fields facilitate crossfile and multifile searching. EXPAND may not be used with super search fields. Use EXPAND with the individual field codes instead.

Search Field Name	Search Code	Fields Searched	Search Examples	Display Codes
Application Number Group	/APPS	AP, PRN	S JP2011-101353/APPS	AI, PRAI, APPS

Property Fields¹⁾

In JPFULL a numeric search for a specific set of physical properties (/PHP) is available within the full text fields (TIEN, AB, DETD, and CLM). The numeric values are not displayed as single fields, but highlighted within the hit displays.

Use EXPAND/PHP to search for all available physical properties. A search with the respective field codes will be carried out in all database fields with English text. The /PHP index contains a complete list of codes and related text for all physical properties available for numeric search.

Field Code	Property	Unit	Symbol	Search Examples
/AOS	Amount of substance	Mol	mol	S 10 /AOS
/BIR	Bit Rate	Bit/Second	bit/s	S 330/BIR
/BIT	Stored Information	Bit	Bit	S BIT > 3 MEGABIT
/CAP	Capacitance	Farad	F	S 1-10 MF/CAP
/CDN	Current Density	Ampere/Square Meter	A/m ²	S CDN>10 A/M**2
/CMOL	Molarity, Molar Concentration	Mol/Liter	mol/L	S UREA/BI (S) 2/CMOL
/CON	Conductance	Siemens	S	S 1S-3/CON
/DB	Decibel	Decibel	dB	S DB>50
/DEG	Degree	Degree	°	S CYLINDER/BI (S) 45/DEG
/DEN	Density (Mass Concentration)	Kilogram/Cubic Meter	kg/m ³	S ANTIBODY/CLM (S) 5E-3-10E-3/DEN
/DEQ	Dose Equivalent	Sievert	Sv	S 2/DEQ
/DOS	Dosage	Milligram/Kilogram	mg/kg	S DOS>0.8
/DV	Viscosity, dynamic	Pascal * Second	Pa * s	S DV>5000
/ECD	Electric Charge Density	Coulomb/Square Meter	C/m ²	S 1 C/M**2 /ECD
/ECH	Electric Charge	Coulomb	C	S 2-3/ECH
/ECO	Electrical Conductivity	Siemens/Meter	S/m	S ECO>800 S/M (5A) METAL
/ELC	Electric Current	Ampere	A	S 1-10/ELC
/ELF	Electric Field	Volt/Meter	V/m	S 650-700/ELF
/ENE	Energy	Joule	J	S TORQUE (5A) 20 - 30 /ENE
/ERE	Electrical Resistivity	Ohm * Meter	Ohm * m	S ERE>2
/FOR	Force	Newton	N	S 50 N /FOR
/FRE	Frequency	Hertz	Hz	S OSCILLAT?/BI (S) 1- 3/FRE
/IU	International Unit	none	IU	S IU>1000 (P) ANTIBIOTIC
/KV	Viscosity, kinematic	Square Meter/Second	m ² /s	S SILICON?/BI (5A) 10E-5 M**2/S /KV
/LEN (or /SIZ)	Length, Size	Meter	m	S 1-4/LEN
/LUME	Luminous Emittance, Illuminance	Lux	lx	S 10-50/LUME
/LUMF	Luminous Flux	Lumen	Lm	S LUMF>1000
/LUMI	Luminous Intensity	Candela	cd	S LUMI<4
/M	Mass	Kilogram	kg	S ALLOY/BI (30A) 1E-10-1E-5/M
/MCH	Mass to Charge Ratio	none	m/z	S MCH=100
/MFD (or /MFS)	Magnetic Flux Density	Tesla	T	S MFD>102
/MFR (or /MFL)	Mass Flow Rate	Kilogram/Second	kg/s	S MFR<0.1
/MM	Molar Mass	Gram/Mol	g/mol	S 2000-3000 G/MOL/MM
/MOLS	Molality of Substance	Mol/Kilogram	mol/kg	S 01.-10 MOL/KG/MOLS
/MVR	Melt Volume Rate	none	g/10 min	S 3/MVR
/NUC	Nutrition Content	none	g/100 kcal	S NUC<100 (P) NUTRIENT
/PER	Percent (Proportionality)	none	%	S POLYMER?/AB (5A) 4/PER
/PERA	Permittivity, Absolute	Farad/Meter	F/m	S DIELECTRIC/BI (S) 4- 4.1/PERA
/PHV	pH Value	pH	pH	S 7.4-7.6/PHV
/POW	Power	Watt	W	S LIGHT/BI (S) ENERGY/BI (S) 350 WATT/POW
/PRES (or /P)	Pressure	Pascal	Pa	S (VACUUM (5A) DISTILL?)/BI (S) 1000-1100/PRES
/RAD	Radioactivity	Becquerel	Bq	S RAD/PHP
/RES	Electrical Resistance	Ohm	Ohm	S SENSOR /BI (S) 10- 100/RES
/RSP	Rotational Speed	Revolution/Minute	rpm	S 2-100/RSP (S) MACHINE/AB
/SAR	Area /Surface Area	Square Meter	m ²	S (COATING? OR FOIL?)/BI (S) 10-100/SAR
/SOL	Solubility	Gram/100 gram	g/100 g	S SOL>20 (10W) WATER
/STSC	Surface Tension	Joule /Square Meter	J/m ²	S 60 J/M**2/STSC
/TCO	Thermal Conductivity	Watt/Meter * Kelvin	W/m * K	S 1/TCO (S) HEAT?
/TEMP (or /T)	Temperature	Kelvin	K	S (REACTION? (10A) ENZYM?) (S) 5/TEMP
/TIM	Time	Second	s	S ?INCUB?/BI (10A) 10-50/TIM

Property Fields (cont'd)

Field Code	Property	Unit	Symbol	Search Examples
/VEL (or /V)	Velocity	Meter per Second	m/s	S REDUC?/BI (S) 1E-3-5E-3/VEL
/VELA	Velocity, angular	Radian/Second	rad/s	S VELA>10
/VLR	Volumetric Flow Rate	Cubic Meter/Second	m ³ /s	S 1-2/VLR (5A) POWDER
/VOL	Volume	Cubic Meter	m ³	S 1E-8-2E-8/VOL.EX
/VOLT	Voltage	Volt	V	S POTENTIAL/CLM (10A) 5E-3 V <VOLT<7E-3 V

- 1) Exponential format is recommended for the search of particularly high or low values, e.g. 1.8E+7 or 1.8E7 (for 18000000) or 9.2E-8 (for 0.000000092).

International Patent Classification (/IPC) Thesaurus

The classifications, validity and catchwords for the main headings and subheadings from the current (8th) edition of the WIPO International Patent Classification (IPC) manual are available. The classifications from the previous editions (1-7) are also available as separate thesauri. To EXPAND and SEARCH in the thesauri for editions 1–7, use the field code followed by the edition number, e.g., /IPC2, for the 2nd edition. Catchwords are included only in the thesauri for the 8th, 7th, 6th, and 5th editions.

Code	Content	Examples
ADVANCED (ADV)	Advanced Codes for the Core Level IPC Code	E A61K0006-06+ADVANCED/IPC
ALL	All Associated Terms (BT, SELF, NT, RT)	E C01C003-00+ALL/IPC
BRO (MAN)	Complete Class	E C01C+BRO/IPC
BT	Broader Term (BT, SELF)	E C01F001-00+BT/IPC
CORE (COR)	Core Codes for the Advanced Level IPC Code	E G08C0019-22+CORE/IPC
ED	Complete title of the SELF term and IPC manual edition	E C01F001-00+ED/IPC
HIE	Hierarchy Term (Broader and Narrower Term) (BT, SELF, NT)	E C01B003-00+HIE/IPC
INDEX	Complete title of the SELF term	E C01F001-00+INDEX/IPC
KT	Keyword Term (catchwords) (SELF, KT)	E CYANOGEN+KT/IPC
NEXT	Next Classification	E C01C001-00+NEXT5/IPC
NT	Narrower Terms (SELF, NT)	E C01C+NT/IPC
PREV	Previous Classification	E C01C001-12+PREV10/IPC
RT (SIB)	Related Terms (SELF, RT)	E C01C003-20+RT/IPC
TI	Complete Title of the SELF Term and Broader Terms (BT, SELF)	E C01F001-00+TI/IPC

ECLA (/EPC) and ICO Thesauri

This thesaurus is available in the /EPC search field (for ECLA codes) and /ICO search field (for 'in-computer-only' codes). All relationship codes can be used with both the EXPAND and SEARCH commands.

Relationship Code	Content	Search Examples
ALL	All usually required terms (BT, SELF, CODE, DEF)	E C12M0001-34H2+ALL/EPC
AUTO (1)	Automatic relationship (BT, SELF, CODE, DEF)	E G01J003-443+AUTO/EPC
BT	Broader terms (BT, SELF)	E G01J0003-443+BT/EPC
CODE	Classification Code (SELF, CODE)	E SCRAPER BIASING MEANS+CODE/EPC
DEF	Definition (SELF, DEF)	E B65G0045-16+DEF/EPC
HIE	Hierarchy terms (all broader and narrower terms) (BT, SELF, DEF, NT)	E A01B0001+HIE/EPC
KT	Keyword terms (SELF, KT)	E LASER+KT/EPC

ECLA-Thesaurus Relationship codes (cont'd)

Relationship Code	Content	Search Examples
MAX	All associated terms	E G01J0003-44B+MAX/EPC
NEXT	Next classification within the same class (SELF, NEXT)	E A01B0001-24+NEXT/EPC
NEXT(n)	Next n classification within the same class	E A01B0001-24+NEXT3/EPC
NT	Narrower terms	E G05B0001-04+NT/EPC
PREV	Previous Code within the same class (SELF, PREV)	E G05B0019-418N1+PREV/EPC
PREV(n)	Previous n classifications within the same class	E G05B0019-418N1+PREV2/EPC
TI	Complete Title of the SELF Term and Broader Terms (BT, SELF)	E G05B0001-03+TI/EPC

(1) Automatic Relationship is SET OFF. In case of SET REL ON, the result of EXPAND or SEARCH without any relationship code is the same as described for AUTO.

CPC Thesaurus

This thesaurus is available in the /CPC search field. All relationship codes can be used with both the EXPAND and SEARCH commands.

Relationship Code	Content	Search Examples
ALL	All usually required terms (BT, SELF, CODE, DEF)	E C12M0001-005+ALL/CPC
AUTO (1)	Automatic relationship (BT, SELF, CODE, DEF)	E G01J003-443+AUTO/CPC
BT	Broader terms (BT, SELF)	E G01J0003-443+BT/CPC
CODE	Classification Code (SELF, CODE)	E CARTRIDGES+CODE/CPC
DEF	Definition (SELF, DEF)	E B65G0045-16+DEF/CPC
HIE	Hierarchy terms (all broader and narrower terms) (BT, SELF, DEF, NT)	E A01B0001+HIE/CPC
KT	Keyword terms (SELF, KT)	E LASER+KT/CPC
MAX	All associated terms	E G01J0003-44+MAX/CPC
NEXT	Next classification within the same class (SELF, NEXT)	E A01B0001-24+NEXT/CPC
NEXT(n)	Next n classification within the same class	E A01B0001-24+NEXT3/CPC
NT	Narrower terms	E G05B0001-04+NT/CPC
PREV	Previous Code within the same class (SELF, PREV)	E G05B0019-00+PREV/CPC
PREV(n)	Previous n classifications within the same class	E G05B0019-00+PREV2/CPC
TI	Complete Title of SELF Term and Broader Terms (BT, SELF)	E G05B0001-03+TI/CPC

DISPLAY and PRINT Formats

Any combination of formats may be used to display or print answers. Multiple codes must be separated by spaces or commas, e.g., D L1 1-5 TI PA. The fields are displayed or printed in the order requested.

The information of the latest publication is displayed by default. To display the content for all levels of the record you can combine all display fields and formats with the qualifier .M except FA, FAM, CFAM, LS, LS2, RE, SCAN, and TRIAL.

For displaying a particular publication of a database record, you can simply add for certain display field the kind code to the appropriate display format, e.g. ALL.A. Fields that allow this are indicated by a number (3).

Hit-term highlighting is available for all fields. Highlighting must be ON during SEARCH to use the HIT, KWIC, and OCC formats.

The default display format is STD.M, i.e., all publication levels of one family in the STD format.

DISPLAY and PRINT Formats

Format	Content	Examples
AB (ABS)	Abstract	D TI AB 1-5
AG	Agent	D AG
AGN	Agent Number	D AGN
AGJA (2)	Agent (Japanese characters)	D AGJA
AI (AP) (1)	Application Information	D AI
AN	Accession Number	D L3 AN
CLM (3)	Claims	D CLM
CLMN (2)	Number of Claims	D CLMN
CPC	Cooperative Patent Classification	D CPC
CPC.TAB	CPC, Tabular	D CPC.TAB
DETD (3)	Detailed Description	D DETD
DETN (2)	Number of Paragraphs in DETD	D DETN
DT (TC)	Document Type	D DT
ED	Entry Date	D ED
EDTX	Entry Date of Fulltext	D EDTX
EPC	European Patent Classification	D EPC
FA	Field Availability (for all publication levels)	D FA
IC	IPC (format contains ICM, ICS)	D IC
ICM	IPC, Main	D IC
ICO	ICO (in-computer-only) Classification	D ICO
ICS	IPC, Secondary	D ICS
IN (AU)	Inventor (in English)	D IN
IN.CNY	Inventor, Country	D IN.CNY
INJA	Inventor (in Japanese)	D INJA
IPCI	IPC, Initial	D IPCI
IPCR	IPC, Reclassified	D IPCR
LA	Language	D LA
LAF	Language of Filing	D LAF
MCLM (3)	Main Claim	D MCLM
PA (CS)	Patent Applicant/Patentee (in English)	D PA
PA.CNY	Patent Applicant, Country	D PA.CNY
PAJA	Patent Applicant/Patentee (in Japanese)	D PAJA
PAN	Patent Assignee Number	D PAN
PI (PN, PATS) (1)	Patent Information	D PI
PIT	Patent Information Publication Type	D PIT
PNO	Patent Number, Original Format	D PNO
PRN (PRAI) (1,5)	Priority Information	D PRN
PRNO (PRAO) (2)	Priority Number, Original Format	D PRNO
RLI (RLN)	Related Patent Information	D RLI
TIEN (TI)	Title (in English)	D TIEN
TIJA	Title (in Japanese)	D TIJA
UP	Update Date	D UP
ALL (1)	AN, ED, EDTX, UP, TIEN, TIJA, IN, IN.CNY, INJA, PA, PA.CNY, PAJA, PAN, LAF, LA, DT, PIT, PI, AI, RLI, PRAI, IPC, CPC, EPC, ICO, AB, DETD, CLM, KT	D ALL
IALL (1)	ALL, indented with text labels	D IALL
DALL (1)	ALL, delimited for post processing	D DALL
APPS (1)	AI, RLN, PRAI	D APPS
BIB (1)	AN, ED, EDTX, UP, TIEN, IN, IN.CNY, PA, PA.CNY, LAF, LA, DT, PIT, PI, AI, RLI, PRAI	D BIB
IBIB (1)	BIB, indented with text labels	D IBIB
BRIEF (1)	AN, ED, EDTX, UP, TIEN, TIJA, IN, IN.CNY, INJA, PA, PA.CNY, PAJA, PAN, LAF, LA, DT, PIT, PI, AI, RLI, PRAI, IPC, CPC, EPC, ICO, AB, MCLM	D BRIEF
IBRIEF (1)	BRIEF, indented with text labels	D IBRIEF
FAM (1)	AN, table of patent family information (from INPADOCDB)	D FAM
CFAM (1)	AN, Condensed family format (from INPADOCDB)	D CFAM
CPC.TAB	CPC, in tabular version	D CPC.TAB
IND	ED, IPC (ICM, ICS, IPCI, IPCR), CPC, EPC, ICO	D IND
IPC	International Patent Classification (ICM, ICS, IPCI, IPCR)	D IPC
IPC.TAB	IPC, IPC.KW, IPC.VER, in tabular version	D IPC.TAB

DISPLAY and PRINT Formats (cont'd)

Format	Content	Examples
LS	Legal Status (from INPADOCDB)	D LS
LS2	Legal Status (from NPADOCDB), detailed version with display headers	D LS2
MAX (ALL.M) (1)	AN, ED, EDTX, UP, TIEN, TIJA, IN, IN.CNY, INJA, PA, PA.CNY, PAJA, PAN, LAF, LA, DT, PIT, PI, AI, RLI, PRAI, IPC, CPC, EPC, ICO, DETD, CLM, FA for all levels of publication	D MAX
IMAX (IALL.M) (1)	MAX, indented with text labels	D IMAX
RE	Citations (from INPADOCDB)	D RE
SCAN (4)	TI (random display without answer numbers)	D SCAN
STD (1)	AN, ED, EDTX, UP, TIEN, TIJA, IN, IN.CNY, INJA, PA, PA.CNY, PAJA, PAN, LAF, LA, DT, PIT, PI, AI, RLI, PRAI, IPC, CPC, EPC, ICO (STD.M is default)	D STD
ISTD (1)	STD, indented with text labels	D ISTD
TRIAL (TRI, SAM, SAMPLE, FREE)	ED, EDTX, UP, TIEN, FA, DETN, CLMN	D TRIAL
TX	DETD, CLM	D TX
HIT	Hit term(s) and field(s)	D HIT
KWIC	Up to 50 words before and after hit term(s) (KeyWord-In-Context)	D KWIC
OCC	Number of occurrences of hit term(s) and field(s) in which they occur	D OCC

- (1) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.
- (2) Custom display only.
- (3) You can combine this display field with the qualifier .PK (Patent Kind Code) to display the content for a certain publication level of a record, e.g. CLM.B2.
- (4) SCAN must be specified on the command line, i.e., D SCAN or DISPLAY SCAN.
- (5) If priority information is not available for a certain document, this information is taken from the application information of this document and marked with an asterisk (*).

SELECT, ANALYZE, and SORT Fields

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

You can combine all fields except FA with the qualifier .M to SELECT/ANALYZE the content of all publication levels.

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Abstract	AB	Y	Y
Accession Number	AN	Y	Y
Agent	AG	Y	Y
Agent Number	AGN	Y	Y
Application Country	AC	Y	Y
Application Date	AD	Y	Y
Application Information	AI (AP, APPS)	Y (2)	Y
Application Year	AY	Y	Y
Claims	CLM	Y	N
CPC Classification	CPC	Y	Y
Detailed Description	DETD	Y (3)	N
Document Type	DT	Y	Y
Entry Date	ED	Y	Y
Entry Date Full Text	EDTX	Y	Y
European Patent Classification	EPC	Y	Y
Field Availability	FA	Y	N

SELECT, ANALYZE, and SORT Fields (cont'd)

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
International Patent Classification	IC	Y	N
Inventor	IN (AU)	Y	Y
Inventor, Country	IN.CNY	Y	Y
ICO (in-computer-only) Classification	ICO	Y	Y
IPC (ICM, ICS, IPCI, IPCR)	IPC	Y	Y
IPC, Advanced Level Symbols	IPC.A	Y (4)	N
IPC, Advanced Level Symbols for Invention	IPC.AI	Y (4)	N
IPC, Initial	IPCI	Y	Y
IPC, Main	ICM	Y	Y
IPC, Reclassified	IPCR	Y	Y
IPC, Reform	IPC.REF	Y	N
IPC, Secondary	ICS	Y	Y
Key Terms	KT	Y	N
Language	LA	Y	Y
Language of Filing	LAF	Y	Y
Main Claim	MCLM	Y	N
Number of Claims	CLMN	Y	Y
Number of Paragraphs in DETD	DETN	Y	Y
Occurrence Count of Hit Terms	OCC	N	Y
Patent Assignee/Patentee	PA (CS)	Y	Y
Patent Assignee, Country	PA.CNY	Y	Y
Patent Assignee, Address	PAA	Y	N
Patent Assignee Number	PAN	Y	Y
Patent Country	PC	Y	Y
Patent Information Publication Type	PIT	Y	Y
Patent Kind Code	PK	Y	Y
Patent Number	PI (PN, PATS)	Y	Y
Patent Number, Original	PNO	Y	Y
Patent Number/Kind Code	PNK	Y	Y
Pre-IPC8 Symbols from the ICM and first IPC8 values from 2006-present	IPC.F	Y (4)	Y
Priority Country	PRC	Y	Y
Priority Date	PRD	Y	Y
Priority Date, First	PRDF	Y	Y
Priority Number	PRN (PRAI)	Y	Y
Priority Number, Original	PRNO	Y	Y
Priority Year	PRY	Y	Y
Priority Year, First	PRYF	Y	Y
Publication Date	PD	Y	Y
Publication Year	PY	Y	Y
Related Patent Country	RLC	Y	Y
Related Application Number	RLN	Y	Y
Related Application Date	RLD	Y	Y
Related Application Year	RLY	Y	Y
Title	TIEN	Y (default)	Y
Update Date	UP	Y	Y

- (1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT T1.
(2) Selects or analyzes application numbers with /AP appended to the terms created by SELECT.
(3) Appends /BI to the terms created by SELECT.
(4) Appends /IPC to the terms created by SELECT.

Sample Records

DISPLAY ALL (STN format)

AN 2011029464 JPFULL ED 20120926 UP 20120926 EDTX 20120926
TIEN METHOD FOR IDENTIFYING HOST CLONE, METHOD FOR PRODUCING MIXTURE OF
ANTIBODIES, METHOD FOR CREATING RECOMBINANT HOST CELL, TRANSGENIC
NON-HUMAN ANIMAL OR PLANT, MIXTURE OF ANTIBODIES, PHARMACEUTICAL
COMPOSITION, AND USE OF MIXTURE OF ANTIBODIES
TIJA 宿主クローンの識別
方法、抗体混合物の
生産方法、組換え宿
主細胞の作出方法、
トランスジェニック
非ヒト動物またはト
ランスジェニック植
物、抗体の混合物、
薬学的組成物、およ
び抗体の混合物の使
用
IN VAN BERKEL PATRICK HENDRIKUS CORNELIS; BRUS RONALD HENDRIK PETER; BOUT
ABRAHAM; LOGTENBERG TON
INJA パトリック
ヘンドリクス
コルネリス ファン
ベルゲル
ロナルド ヘンドリッ
ク ペーター ブルス
アブラハム ボウト
トン ログテンベルグ
PA MERUS BV;
PAJA メルス ベー ヴァー;
オランダ国 3 5 8 4
セーテー ユトレヒト
ウップサララーン 8
PAN 510098102
LAF Japanese
LA Japanese
DT Patent; (Fulltext)
PIT JPA DOC. LAID OPEN TO PUBL. INSPEC. [PUBLISHED FROM 1971 ONWARDS]
PI JP 2011177193 A 20110915
AI JP 2011-121054 20110530
RLN WO 2003-EP50201 20030527
PRAI EP 2002-77953 20020718
US 2002-397066P 20020718
WO 2003-EP50201 20030527
IPCI C12N0015-09 [I,A]; A01H0005-00 [I,A]; A01K0067-27 [I,A]
IPCR A61K0039-00 [I,A]; A61K0039-395 [I,A]; A61P0031-04 [I,A]; A61P0031-12
[I,A]; A61P0035-00 [I,A]; A61P0035-02 [I,A]; A61P0035-04 [I,A];
A61P0037-06 [I,A]; C07K0014-00 [I,A]; C07K0016-00 [I,A]; C07K0016-10
[I,A]; C07K0016-28 [I,A]; C07K0016-30 [I,A]; C07K0016-32 [I,A];
C12N0015-00 [I,A]; C12P0021-02 [I,A]; C12P0021-08 [I,A]
EPC C07K0016-00; C07K0016-10; C07K0016-28A; C07K0016-28A28; C07K0016-28C;
C07K0016-28Z; C07K0016-30; C07K0016-32
ICO M07K0317:120; M07K0317:210; M07K0317:310; M07K0317:500;

JPFULL

M07K0317:510; M07K0317:622; M07K0317:626; M07K0317:730; M07K0319:30

AB

Original

PROBLEM TO BE SOLVED: To provide a method for producing a mixture of antibodies from a single host cell clone.

SOLUTION: The invention provides the methods for producing mixtures of antibodies from a single host cell clone. Additionally, a nucleic acid sequence encoding a light chain, and nucleic acid sequences encoding different heavy chains are expressed in a recombinant host cell. The antibodies in the mixtures suitably comprise identical light chains paired to different heavy chains pairing to the light chain, thereby forming functional antigen binding domains. The mixtures of antibodies are also provided. Such mixtures can be used in a variety of fields.

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DETD

TECHNICAL FIELD. [0001] (Field of invention) as for this invention, field of medicine, furthermore as for details, field of production of antibody, from as for details, it regards the production of the blend of the antibody more.

BACKGROUND ART. [0002] (The background of invention) essential function of immunity type is the defense for infection. Body fluids characteristic immunity system seems like the pathogenic agent, opposes to the molecule which is recognized fault - as oneself, making use of the immunoglobulin. ...

CLM

1. It rearranges the blend of the antibody and in the landlord, it produces being the method where, this method the following: In the rearrangement host cell, at least it is light the chain and ...
2. As the aforementioned rearrangement host cell, the antibody which is produced commonness lightly included the chain, heavily the chain and involution possible commonness where the description above at least 3 kinds differ lightly the nuclear acid arrangement which encodes the chain is included, method of claim 1 statement.
3. Furthermore, the following: The antibody from the host cell, or the process which is collected from the host cell culture It includes, claim method of 1 or 2 statements.

DISPLAY IBIB

ACCESSION NUMBER: 2011040790 JPFULL
 ENTRY DATE: 20120926
 UPDATE DATE: 20120926
 ENTRY DATE (FULLTEXT): 20120926
 TITLE (ENGLISH): USE OF GLASS FOR APPLICATION TO PHOTOVOLTAIC POWER GENERATION
 INVENTOR(S): FAFNER JORG OTTO FRANZ SPAIGHT BURCKHARD
 PATENT APPLICANT(S): SCHOTT AG;
 PATENT APPLICANT NUMBER: 504299782
 LANGUAGE OF FILING: Japanese
 LANGUAGE OF PUBL.: Japanese
 DOCUMENT TYPE: Patent; (Fulltext)
 PATENT INFORMATION TYPE: JPA DOC. LAID OPEN TO PUBL. INSPEC. [PUBLISHED FROM 1971 ONWARDS]
 PATENT INFORMATION: JP 2011258954 A 20111222
 APPLICATION INFO.: JP 2011-128030 20110608
 PRIORITY INFO.: DE 2010-102010023366 20100610

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